Abstracts

An Application of Membrane Probes for On-Wafer Testing of Unmatched High Power MMICs

D. Tonks, W. Vaillancourt, K. Smith and E. Strid. "An Application of Membrane Probes for On-Wafer Testing of Unmatched High Power MMICs." 1996 MTT-S International Microwave Symposium Digest 96.3 (1996 Vol. III [MWSYM]): 1289-1292.

A membrane probe capable of determining large signal power handling capabilities of discrete and partially matched large periphery FETs at microwave frequencies has been developed. This paper describes the application and implementation of a membrane probe for a 15.7 mm partially matched 6W power amplifier MMIC that employs off-chip matching networks for a high volume multichip module application.

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